

das·AMO

in partnership with:



Fraunhofer



Onyx

Graphene and 2D  
Materials Inspector

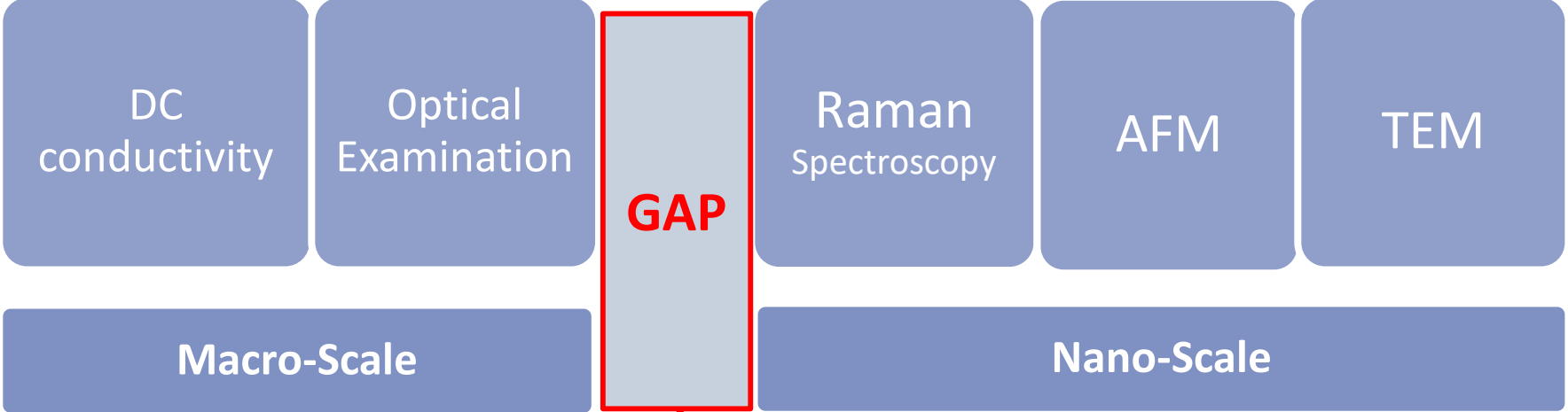


das·AMO

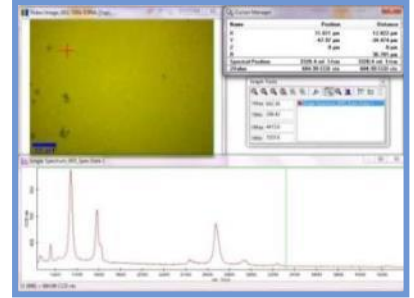
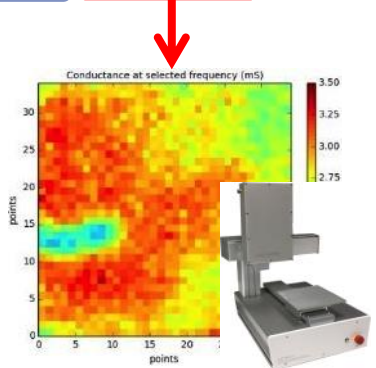


ONYX

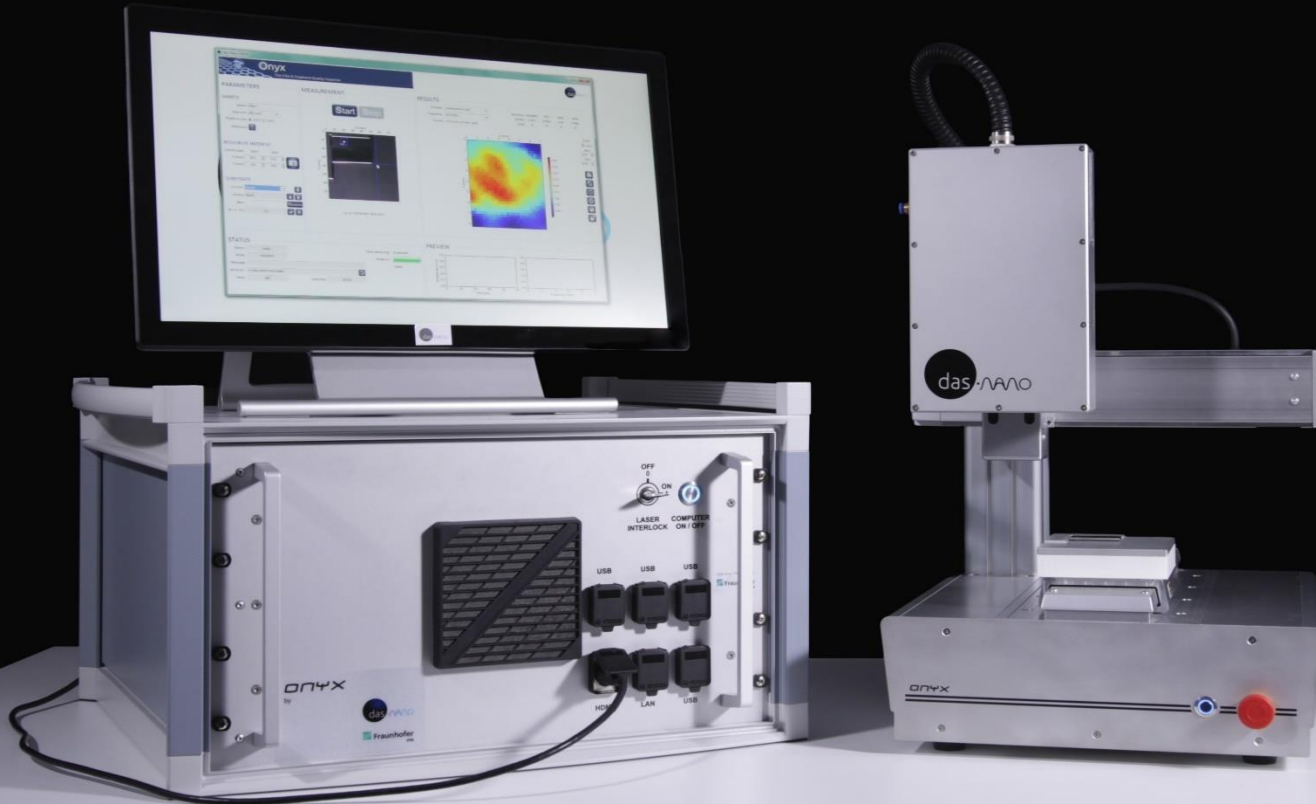
# Main Current Characterization Methods



**ISO TC 113**



# Onyx system





# VIDEO ONYX

<https://youtu.be/V07JrlehjFg>

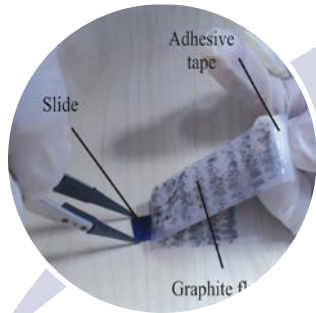
# 2D Materials Evolution

Production Stages



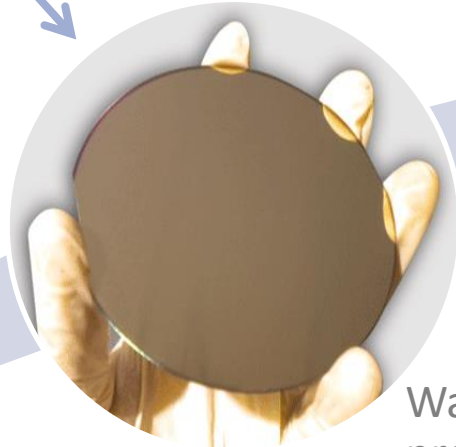
Onyx

FULL SURFACE INSPECTION



Laboratory  
research

[mm<sup>2</sup>]



Wafer  
production

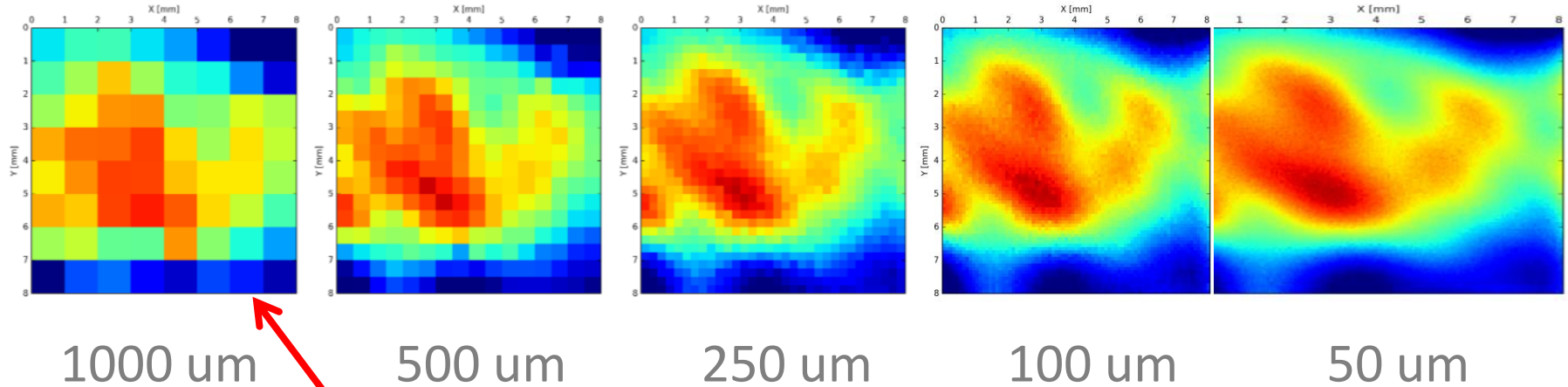
[cm<sup>2</sup>]



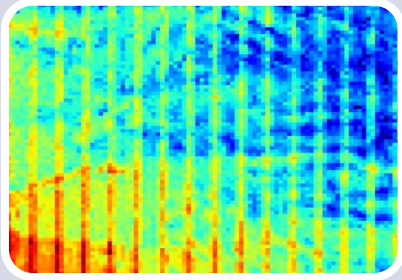
Industrial  
Material

[m<sup>2</sup>]

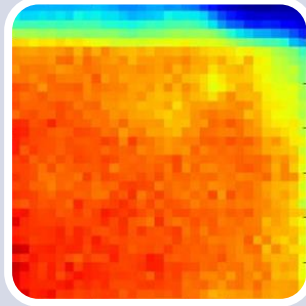
## Same Sample 10x10mm – Different Lateral resolution



**Even the lowest resolution, provides meaningful information**

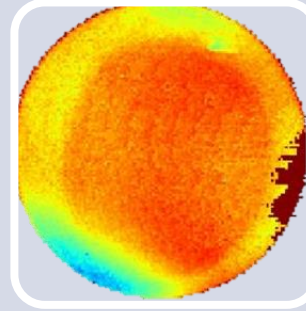
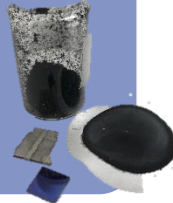


## PHOTOVOLTAIC



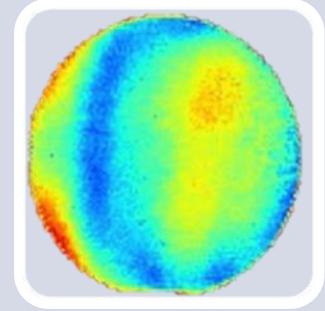
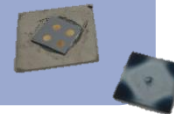
## GRAPHENE

- CDV
- Epitaxial
- Multilayer
- Flakes
- Inks



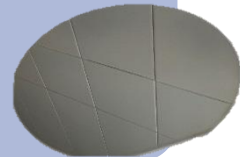
## 2D MATERIALS

- ITO
- GaN
- PEDOT
- Cellulose
- ALD



## ELECTRONICS

- Wafers
- Small area
- Semiconductors



# Substrates

Quartz  
Glass  
Soda Lime Glass  
Silicon  
Silicon Carbide (SiC)  
Silicon Oxide  
Sapphire  
Cellulose  
Paper  
Silicon  
NbC  
PET  
AZO  
Ge, Sb

...





## QUALITY MAP

- Quick Quality control
- Full conductance analysis
- Single Side Measurement
- 100% Area Inspection

## UNIQUE FEATURES

- Ultra Fast Option: 12 cm<sup>2</sup>/min
- High Resolution: 50 μm
- Custom Substrate Characterization
- Fully Automated



We're looking forward to hearing from you!



Polígono Industrial Mutilva Baja, Calle G, 6  
31192 - Mutilva Baja, Navarra, Spain

*phone:* +34 948 246295

<http://www.das-nano.com/>

*email:* [admin@das-nano.com](mailto:admin@das-nano.com)